

## **MODELING ENVIRONMENTAL DEGRADATION IN SiC/BN/SiC CMCS**

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In the first part of this presentation we will discuss the Environmental Degradation Model for SiC/BN/SiC CMC (Parthasarathy et al., 2018), its scope and limitations, and the recent experience of integrating it with FEA. Examples of application of the integrated environmental/mechanical model to the behavior of unidirectional CMC panels under combined effects of applied load and environmental factors will be presented, and lessons learned will be discussed. In the second part of then talk we will consider future development and expansion of the model.